



**SLOVENSKI STANDARD**  
**SIST EN IEC 60749-5:2024**

**01-marec-2024**

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**Polprevodniški elementi - Mehanske in klimatske preskusne metode - 5. del:  
Preskus življenjske dobe v dinamičnem ravnotežju vlažnosti in pri ustaljeni  
temperaturi (IEC 60749-5:2023)**

Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test (IEC 60749-5:2023)

Halbleiterbauelemente - Mechanische und klimatische Prüfverfahren - Teil 5:  
Lebensdauerprüfung bei konstanter Temperatur und Feuchte unter elektrischer  
Beanspruchung (IEC 60749-5:2023)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 5:  
Essai continu de durée de vie sous température et humidité avec polarisation (IEC  
60749-5:2023)

[SIST EN IEC 60749-5:2024](https://standards.iteh.ai/SIST-EN-IEC-60749-5-2024)

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**Ta slovenski standard je istoveten z: EN IEC 60749-5:2024**

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**ICS:**

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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**SIST EN IEC 60749-5:2024**

**en**



EUROPEAN STANDARD  
NORME EUROPÉENNE  
EUROPÄISCHE NORM

**EN IEC 60749-5**

January 2024

ICS 31.080.01

Supersedes EN 60749-5:2017

English Version

**Semiconductor devices - Mechanical and climatic test methods -  
Part 5: Steady-state temperature humidity bias life test  
(IEC 60749-5:2023)**

Dispositifs à semiconducteurs - Méthodes d'essais  
mécaniques et climatiques - Partie 5: Essai continu de  
durée de vie sous température et humidité avec polarisation  
(IEC 60749-5:2023)

Halbleiterbauelemente - Mechanische und klimatische  
Prüfverfahren - Teil 5: Lebensdauerprüfung bei konstanter  
Temperatur und Feuchte unter elektrischer Beanspruchung  
(IEC 60749-5:2023)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels**

## EN IEC 60749-5:2024 (E)

### European foreword

The text of document 47/2820/FDIS, future edition 3 of IEC 60749-5, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60749-5:2024.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2024-10-23
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2027-01-23

This document supersedes EN 60749-5:2017 and all of its amendments and corrigenda (if any).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

### Endorsement notice

The text of the International Standard IEC 60749-5:2023 was approved by CENELEC as a European Standard without any modification.

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cencenelec.eu](http://www.cencenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-4	-	Semiconductor devices - Mechanical and climatic test methods - Part 4: Damp heat, steady state, highly accelerated stress test (HAST)	EN 60749-4	-

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